

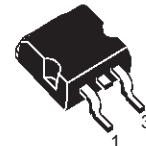


STB70NFS03L

N-CHANNEL 30V - 0.008 Ω - 70A D²PAK STripFET™ MOSFET PLUS SCHOTTKY RECTIFIER

PRELIMINARY DATA

MAIN PRODUCT CHARACTERISTICS			
MOSFET	V _{DSS}	R _{DS(on)}	I _D
	30 V	<0.01 Ω	70 A
SCOTTKY	I _{F(AV)}	V _{RRM}	V _{F(MAX)}
	3 A	30 V	0.51 V

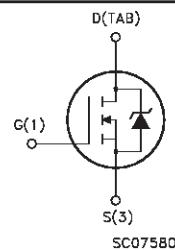


D²PAK
TO-263
(suffix "T4")

DESCRIPTION

This product associates a Power MOSFET of the third generation of STMicroelectronics unique "Single Feature Size" strip-based process and a low drop Schottky diode. The transistor shows the best trade-off between on-resistance and gate charge. Used as low side in buck regulators, the product is the best solution in terms of conduction losses and space saving.

INTERNAL SCHEMATIC DIAGRAM



MOSFET ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V _{DGR}	Drain-gate Voltage (R _{GS} = 20 kΩ)	30	V
V _{GS}	Gate-source Voltage	± 22	V
I _D	Drain Current (continuos) at T _C = 25°C	70	A
I _D	Drain Current (continuos) at T _C = 100°C	50	A
I _{DM(•)}	Drain Current (pulsed)	280	A
P _{tot}	Total Dissipation at T _C = 25°C	100	W
	Derating Factor	0.67	W/°C
T _{stg}	Storage Temperature	-65 to 175	°C
T _j	Max. Operating Junction Temperature	175	°C

(•)Pulse width limited by safe operating area

SCHOTTKY ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{RRM}	Repetitive Peak Reverse Voltage	30	V
I _{F(RMS)}	RMS Forward Current	20	A
I _{F(AV)}	Average Forward Current	T _L =125 °C d=0.5	A
I _{FSM}	Surge Non Repetitive Forward Current	tp=10ms Sinusoidal	A
dv/dt	Critical Rate of Rise of Reverse Voltage	75	V/μs

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THERMAL DATA

$R_{thj-case}$	Thermal Resistance Junction-case Max	Max	1.5	°C/W
$R_{thj-amb}$	Thermal Resistance Junction-ambient Max	Max	62.5	°C/W
T_j	Maximum Lead Temperature For Soldering Purpose		175	°C

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^\circ\text{C}$ unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	$I_D = 250 \mu\text{A}$ $V_{GS} = 0$	30			V
I_{DSS}	Zero Gate Voltage Drain Current ($V_{GS} = 0$)	$V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating}, T_C = 125^\circ\text{C}$			1 10	μA μA
I_{GSS}	Gate-body Leakage Current ($V_{DS} = 0$)	$V_{GS} = \pm 20 \text{ V}$			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250 \mu\text{A}$	1			V
$R_{DS(on)}$	Static Drain-source On Resistance	$V_{GS} = 10 \text{ V}$ $I_D = 35 \text{ A}$ $V_{GS} = 5 \text{ V}$ $I_D = 18 \text{ A}$		0.008 0.015	0.01 0.018	Ω Ω
$I_{D(\text{on})}$	On State Drain Current	$V_{DS} > I_{D(\text{on})} \times R_{DS(\text{on})\text{max}}$ $V_{GS} = 10 \text{ V}$	70			A

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs}^{(*)}$	Forward Transconductance	$V_{DS} > I_{D(\text{on})} \times R_{DS(\text{on})\text{max}}$ $I_D=35 \text{ A}$		40		S
C_{iss} C_{oss} C_{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitances	$V_{DS} = 25 \text{ V}$ $f = 1 \text{ MHz}$ $V_{GS} = 0$		1470 490 110		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)**SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on Delay Time Rise Time	$V_{DD} = 15 \text{ V}$ $I_D = 35 \text{ A}$ $R_G = 4.7 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, Figure 3)		20 350		ns ns
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 24 \text{ V}$ $I_D = 46 \text{ A}$ $V_{GS} = 10 \text{ V}$		35 5 10	45	nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$ t_f	Turn-off Delay Time Fall Time	$V_{DD} = 24 \text{ V}$ $I_D = 35 \text{ A}$ $R_G = 4.7 \Omega$ $V_{GS} = 10 \text{ V}$ (Resistive Load, see fig.3)		35 65		ns ns

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} $I_{SDM(\bullet)}$	Source-drain Current Source-drain Current (pulsed)				70 280	A A
$V_{SD} (*)$	Forward On Voltage	$I_{SD} = 70 \text{ A}$ $V_{GS} = 0$			1.5	V
t_{rr} Q_{rr} I_{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 70 \text{ A}$ $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 15 \text{ V}$ $T_j = 150 \text{ }^\circ\text{C}$ (see test circuit, Figure 5)		70 105 2.4		ns nC A

(*)Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %.

(*)Pulse width limited by safe operating area.

SCHOTTKY STATIC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$I_R (*)$	Reversed Leakage Current	$T_j = 25 \text{ }^\circ\text{C}$ $V_R = 30 \text{ V}$ $T_j = 125 \text{ }^\circ\text{C}$ $V_R = 30 \text{ V}$		0.03	0.2 100	mA mA
$V_F (*)$	Forward Voltage Drop	$T_j = 25 \text{ }^\circ\text{C}$ $I_F = 3 \text{ A}$ $T_j = 125 \text{ }^\circ\text{C}$ $I_F = 3 \text{ A}$		0.38	0.51 0.46	V V

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Fig. 1: Unclamped Inductive Load Test Circuit

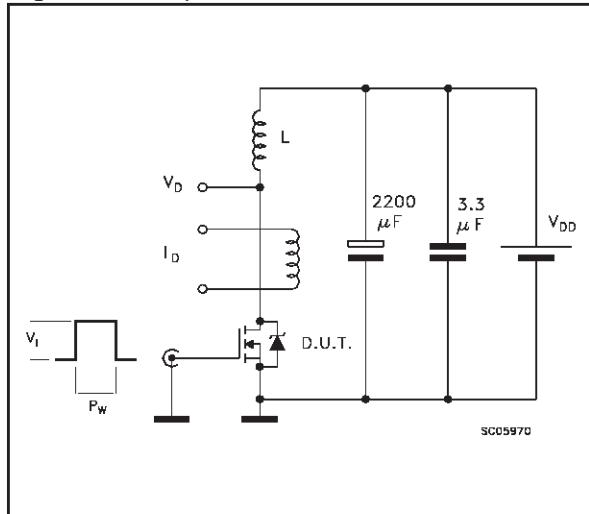


Fig. 2: Unclamped Inductive Waveform

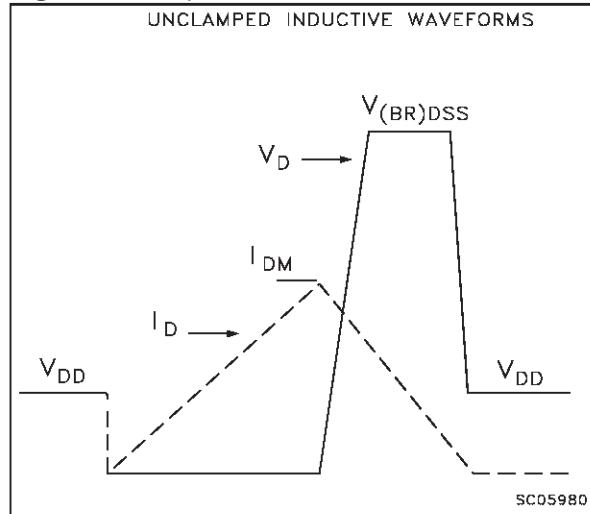


Fig. 3: Switching Times Test Circuits For Resistive Load

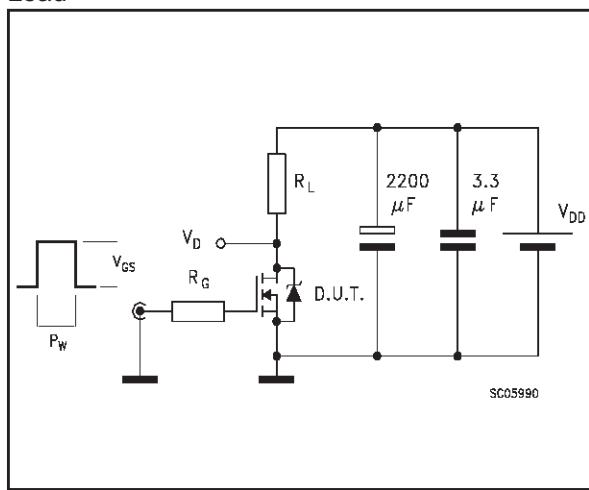


Fig. 4: Gate Charge test Circuit

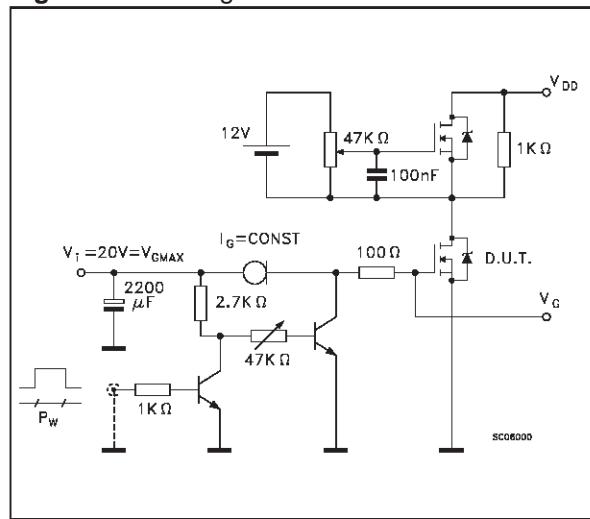
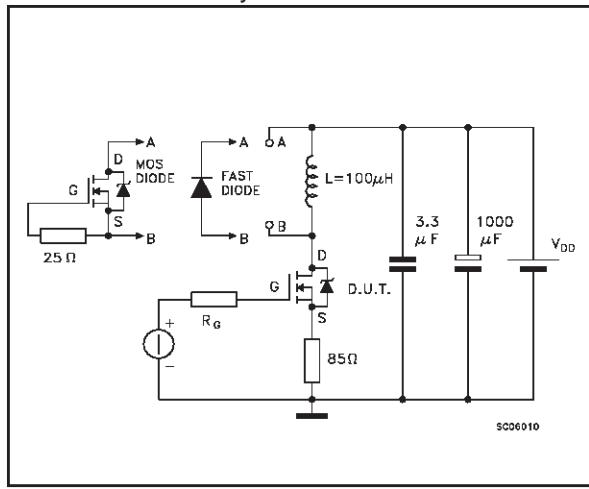
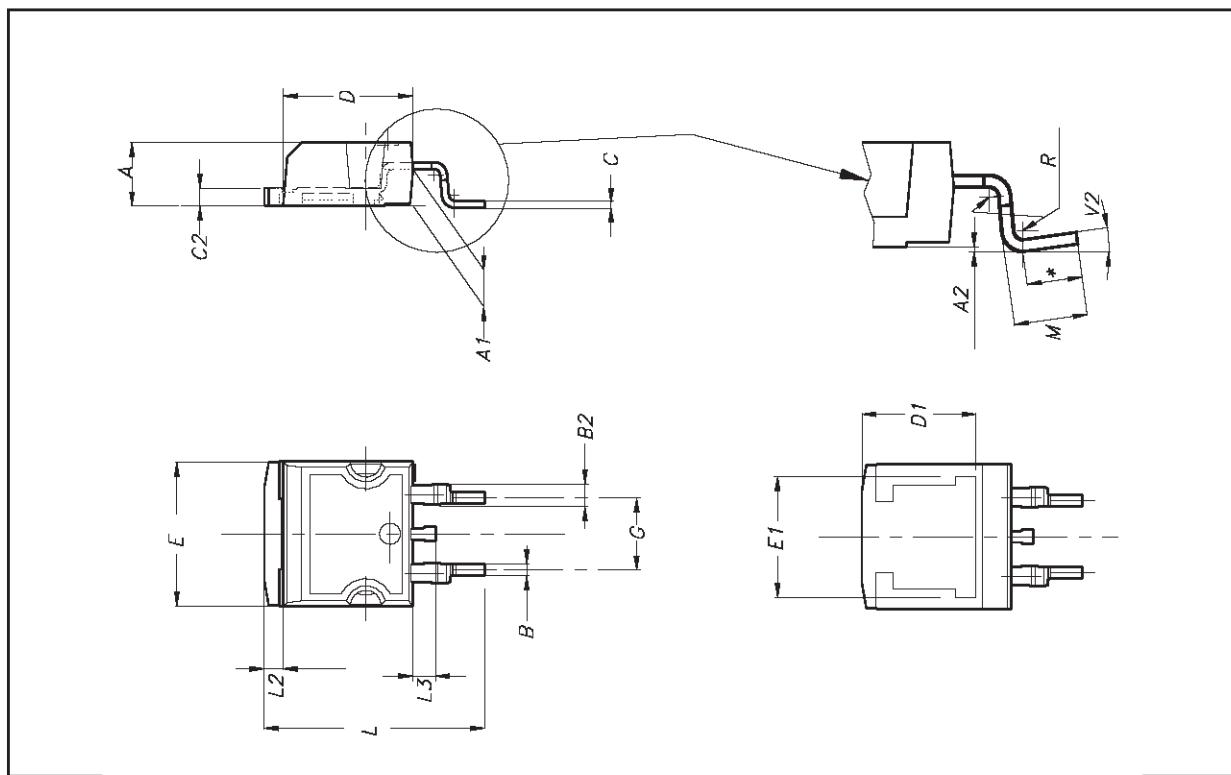


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



D²PAK MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.4		4.6	0.173		0.181
A1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
B	0.7		0.93	0.027		0.036
B2	1.14		1.7	0.044		0.067
C	0.45		0.6	0.017		0.023
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1		8			0.315	
E	10		10.4	0.393		
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.590		0.625
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.068
M	2.4		3.2	0.094		0.126
R		0.4			0.015	
V2	0°		8°			



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